Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/693,151	HAN, JOHN MING-CHUAN
Examiner	Art Unit
/BINH K. TIEU/	2614

SEARCHED						
Cla	as <b>s</b>	Subclass	Date		Examiner	
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		114.27				
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INT	INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner				

SEARCH NO (INCLUDING SEARCI		)
	DATE	EXMR
WEST DATABASES SEARCH	12/3/2007	вкт
WEST DATABASES SEARCH	12/5/2007	вкт
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